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PATENT NUMBER and
ISSUE DATE

U.S. UTILITY Patent Application

APPL NUM 10063295	FILING DATE 04/09/2002	CLASS 331	SUBCLASS 57	CAU 2817	EXAMINER Shingleton AHS
**APPLICANTS: Abadeer Wagdi; Ellis Wayne; Hansen Patrick; McKenna Jonathan;					
*CONTINUING DATA VERIFIED:					
**FOREIGN APPLICATIONS VERIFIED:					
PG-PUB <input type="checkbox"/> DO NOT PUBLISH <input type="checkbox"/> RESCIND <input type="checkbox"/>					
Foreign priority claimed <input type="checkbox"/> yes <input type="checkbox"/> no 35 USC 119 conditions met <input type="checkbox"/> yes <input type="checkbox"/> no				ATTORNEY DOCKET NO BUR920010127	
TITLE : System and method for measuring circuit performance degradation due to PFET negative bias temperature instability (NBTI)					

U.S. DEPT. OF COMMERCE PAT & TM-PTO-436L (Rev. 12-94)

NOTICE OF ALLOWANCE MAILED		CLAIMS ALLOWED	
		Total Claims	Print Claims for O.G.
ISSUE FEE		DRAWING	
Amount Due	Date Paid	Sheets Drawn	Figs. Drawn
			12
		Application Examiner	
<input type="checkbox"/> TERMINAL DISCLAIMER		PREPARED FOR ISSUE	
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